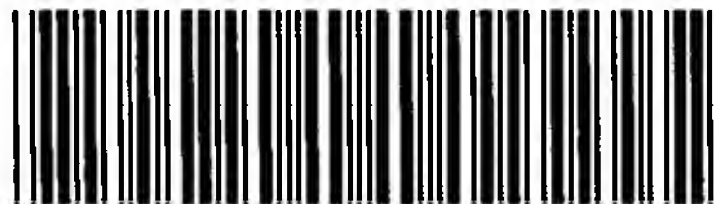


**Search Notes**

Application/Control No.

10/566,988

Examiner

Seung H. Lee

Applicant(s)/Patent under  
Reexamination

MIURA ET AL.

Art Unit

2876

**SEARCHED**

Class	Subclass	Date	Examiner
235	451	9/17/2007	SL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
235/492	9/17/2007	SL
EAST	9/17/2007	SL